# Session OO

## Microwave Probe Measurements

**Chairman:**

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Microwave probing measurements have become a fundamental measurement technique for testing microwave circuits, this includes on-wafer, MMIC, etc. This session covers current developments in the field. A new coaxial style probe is presented that exhibits broadband, low loss and low VSWR characteristics with prospects of low cost for high volume testing. A wide number of measurement applications are presented with an emphasis on mm-frequencies as high as 300 GHz. An active probe for full two-port Vector Network Analysis to 120 GHz is reported along with an innovative matching structure for on wafer measurements. Electro-optic/photoconductive probe sampling techniques using time domain network analysis are also presented.

**10:30 a.m.–12:00 p.m., Thursday, June 17, 1993**
**Room 215**